



US00D835802S

(12) **United States Design Patent** (10) **Patent No.:** **US D835,802 S**
Ito et al. (45) **Date of Patent:** **** Dec. 11, 2018**

(54) **SUBSTRATE FOR SPECTROSCOPIC ANALYSIS**

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(**) Term: **15 Years**

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(30) **Foreign Application Priority Data**

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(51) **LOC (11) Cl.** **24-02**

(52) **U.S. Cl.**

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CPC **G01N 1/405** (2013.01)

(58) **Field of Classification Search**

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D10/80, 81; 422/502–507, 430, 560–566,
422/68.1, 69, 547; 435/288.2–288.5,
435/283.1, 289.1, 44, 46

CPC B01J 19/0046; B01J 2219/00596; G01N
1/405; G01N 35/00009; G01N 1/312;
B01L 2300/0816; B01L 2400/0406; B01L
9/54; B01L 9/06; B01L 9/52; B01L
9/543; B01L 9/00; B01L 3/5085; B01L
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See application file for complete search history.

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(Continued)

Primary Examiner — Richard E Chilcot

(57) **CLAIM**

The ornamental design for a substrate for spectroscopic analysis, as shown and described.

DESCRIPTION

1. Substrate for spectroscopic analysis

1.1 : Perspective

1.2 : Front

1.3 : Back

1.4 : Top

1.5 : Bottom

1.6 : Left

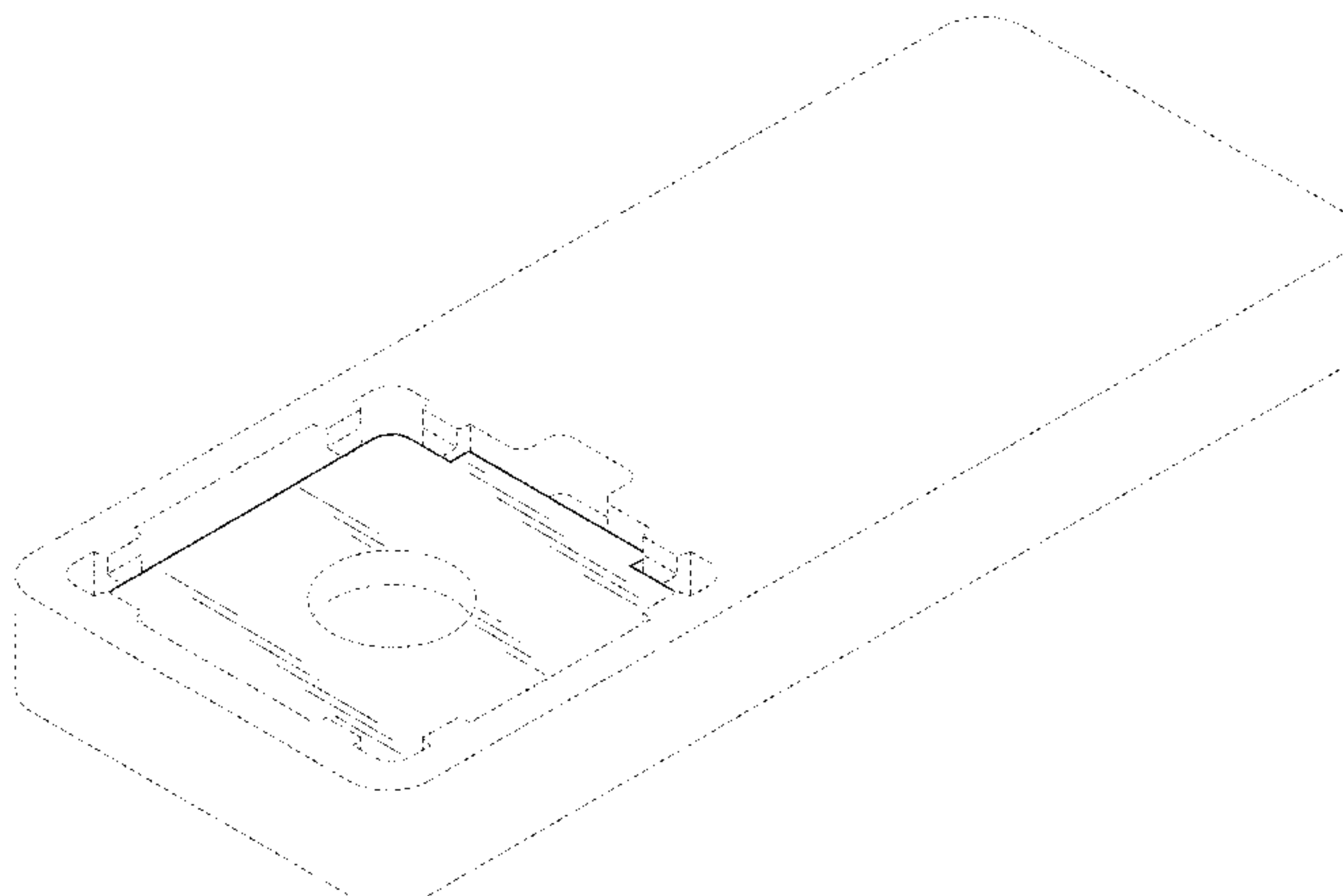
1.7 : Right

1.8 : SECTIONAL VIEW

1.9 : SECTIONAL VIEW

The broken line showing the substrate for spectroscopic analysis is for the purpose of illustrating environmental structure and forms no part of the claimed design.

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The dot-dash broken lines define the bounds of the claimed design and form no part thereof.

1 Claim, 9 Drawing Sheets

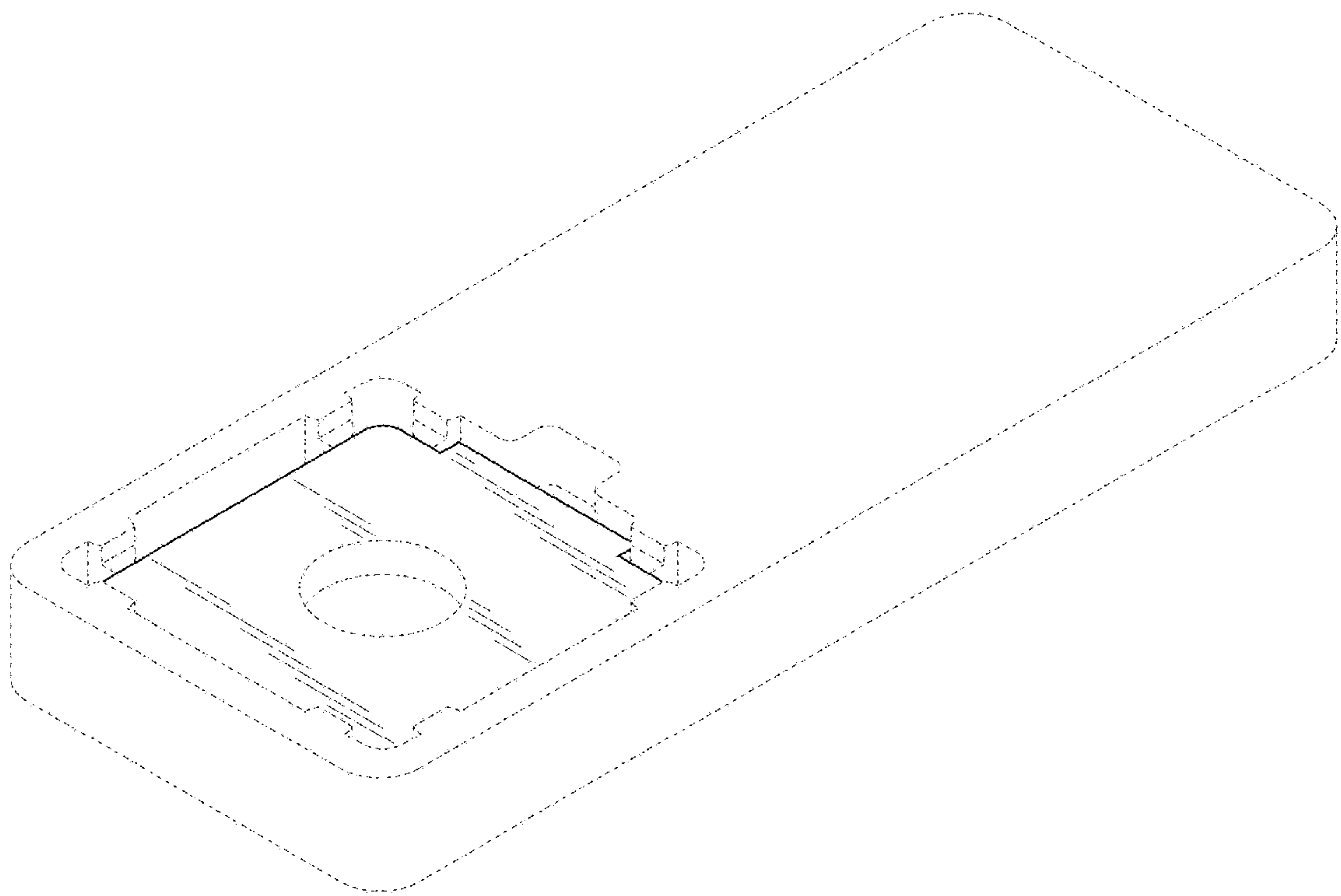
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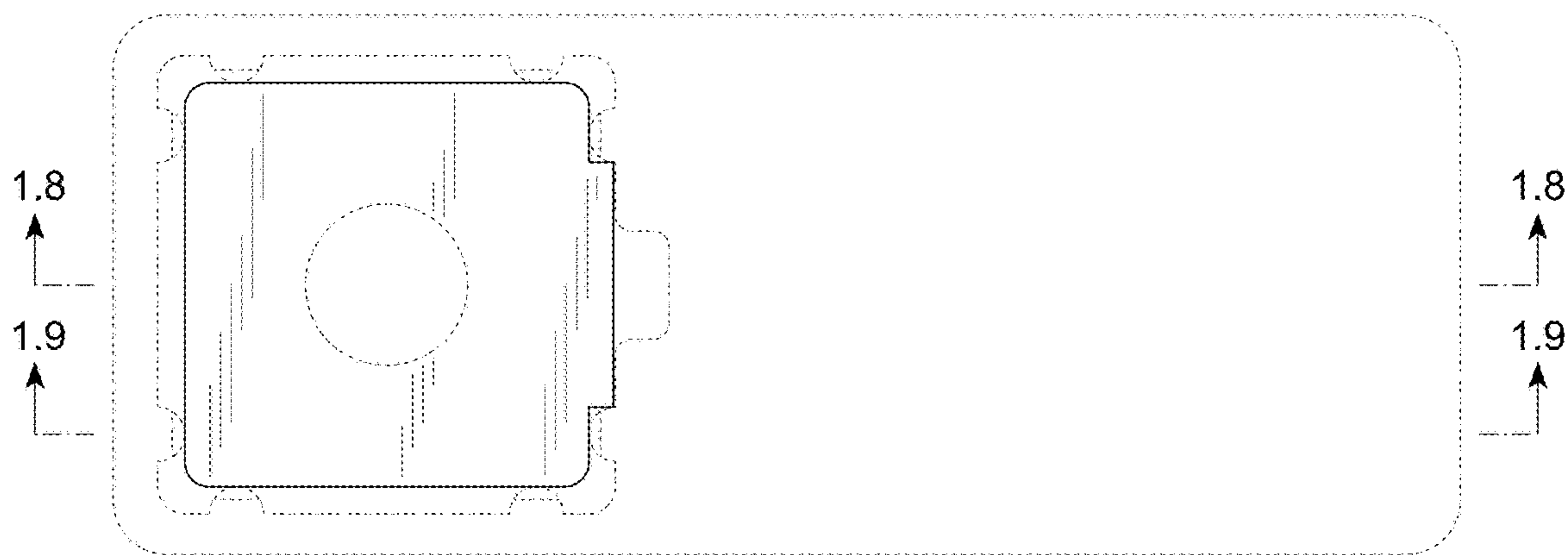
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1.1



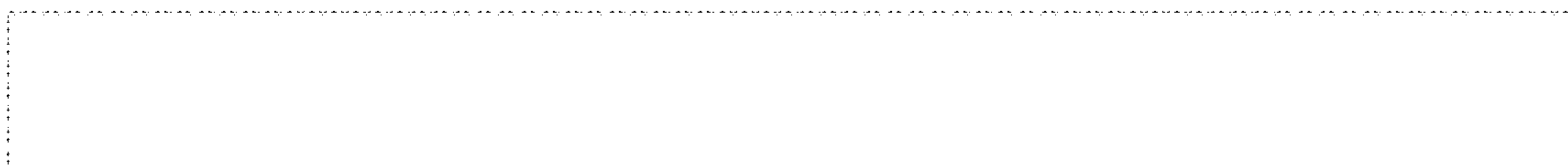
1.2



1.3



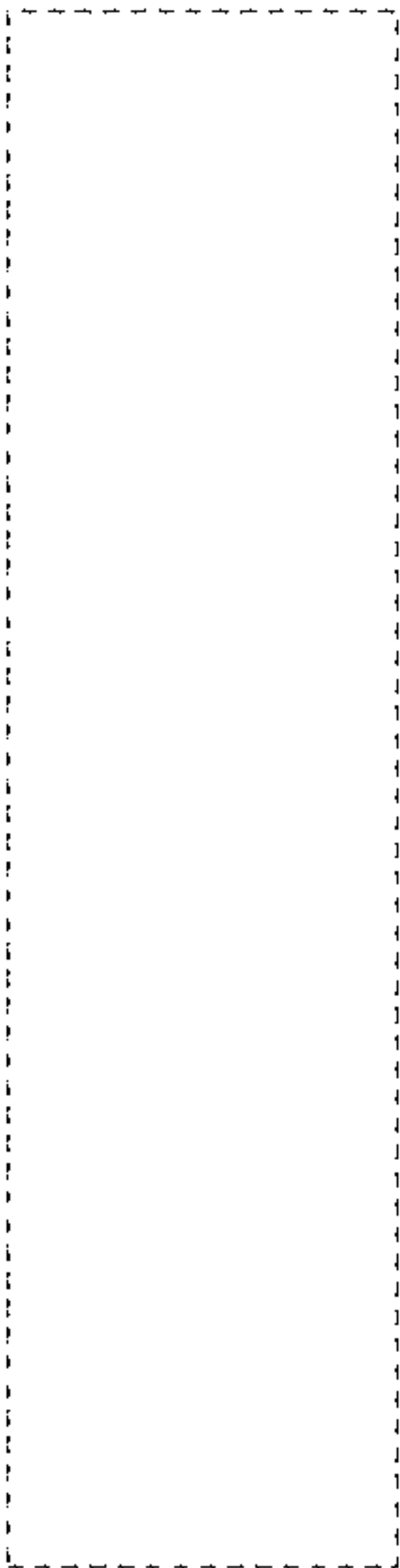
1.4



1.5



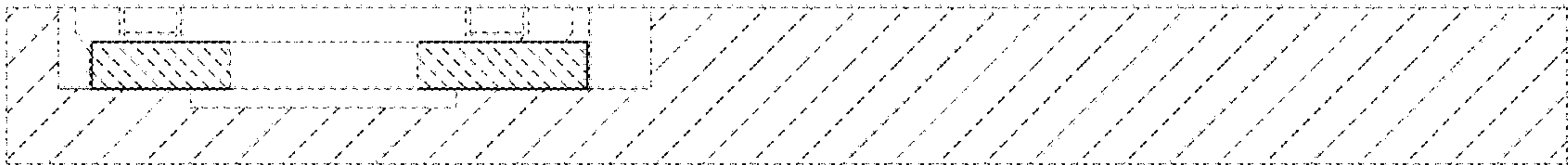
1.6



1.7



1.8



1.9

